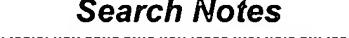


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/627,316	NEILL ET AL.
	Examiner	Art Unit
	Chuc D. Tran	2821

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner